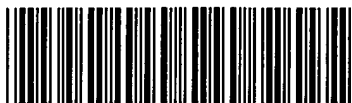


Search Notes

Application/Control No.

10/650,574

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

KIM ET AL.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385	52,88,90, 97	3/14/2005	JDS JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	3/14/2005	JDS JDS
INSPEC and IEEE databases: waveguide, planar, fiber, substrate, alignement, table, surface, rotation	3/15/2005	JDS JDS